

Notice of References Cited

Application/Control No.	Applicant(s)/Patent Under Reexamination 09/489,760 GOULMY ET AL.	
Examiner	Art Unit "Neon" Phuong Huynh 1644	

Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	Stryer et al, in Biochemistry, W.H. Freeman and Company, New York, pages 31-33, 1988.
	V	Ngo et al, in The Protein Folding Problem and Tertiary Structure Prediction, pp. 492-495, 1994.
	W	Tisch et al, Proc. Natl. Acad. Sci. USA 91: 437-438, 1994.
	X	Anderton et al, Immunology 104: 367-76, 2001.

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) References cited in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References CitedApplication/Control No.
09/489,760Applicant(s)/Patent Under
Reexamination
GOULMY ET AL.Examiner
"Neon" Phuong HuynhArt Unit
1644
Page 2 of 2**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Peakman et al, Immunology 104: 361-366, 2001.
	V	
	W	
	X	

copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.